

**Q2 (a) Write the basic structure of NMOS transistor for enhancement and depletion mode indicating all layers.**

**Answer** Page Number 8, Figure 1.4 a, b of Text Book

**Q2 (b) With neat sketch explain the NMOS n-well Fabrication process.**

**Answer** Page Number 12 of Text Book

**Q2 (c) Compare CMOS technology with Bipolar technology.**

**Answer**

Cmos = Low static power high noise margin pallang quality low o/p quick  
Bipolar = high static power low noise margin low poeing high o/p drive

**Q3 (a) Derive an expression for  $I_{ds}$  in terms of  $K$ ,  $(W/L)$  ratio and  $V_{ds}$  in both saturation and non – saturation.**

**Answer**

$$I_{ds} = Qc/p, Tsd = L/v = \frac{b^2}{\mu v ds}$$

$$Qc = E_g E_{ins} E_o WL$$

$$= WL E_{ins} E_o / D [(V_{gs} - V_t) - V_{ds} / 2]$$

∴ non saturation region

$$I_{ds} = E_{ins} E_{oll} / D w/L [(V_{gs} - V_t) - v_{ds} / 2] v_{ds}$$

$$= K$$

$$I_{ds} = \beta [(V_{gs} - V_t) V_{ds} - (V_{ds})^2 / 2]$$

Saturation region

$$I_{ds} = k \frac{W}{L} \left( \frac{V_{gs} - V_t}{2} \right)^2$$

$$I_{ds} = \frac{\beta}{2} (V_{gs} - V_t)^2$$

**Q3 (b) With neat circuit diagrams explain the various form of pull up used in MOS circuits. Compare the merits and demerits of each.**

**Answer**

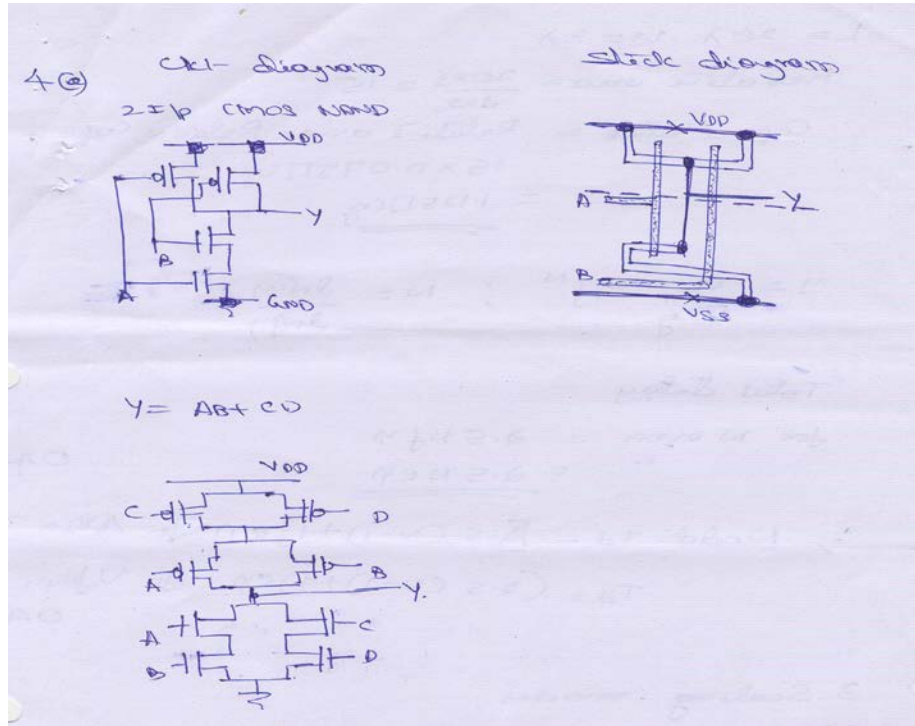
Page Number 45-47 Textbook

1. Load resistance RI
2. NMOS depletion mode Transistors pull up
3. NMOs enhanced mode Transistor pull up
4. C Mos pull-up

**Q4 (a) Write the circuit and stick diagram for**

- (i) two input CMOS NAND gate
- (ii)  $y = AB + CD$

Answer



Q4 (b) Write the design rules of transistor, wires and contacts. Explain briefly with neat sketch

Answer Page Number 74-75 Textbook

Q5 (b) Calculate the capacitance of a metal layer with  $L = 20 \lambda$  and width  $= 3 \lambda$  in terms of standard unit of capacitance.

Answer

$$L = 20 \lambda \quad W = 3 \lambda$$

$$\text{Relative area} = 20 \times 3 / 2 \times 2 = 15$$

$$\text{Capacitance} = \text{Relative area} \times \text{Relation}$$

$$15 \times 0.075 \text{ fF} = 1.125 \text{ fF}$$

Q5 (c) Derive an expression for total delay of N inverters (NfMOS) connected in cascaded form to drive a large capacitive load.

Answer

$$y = C_L / C_g = f^N$$

$$N = \ln(y) / \ln(f)$$

Total delay

$$\text{For } N \text{ even} = 2.5N t_{p}$$

$$=2.5Nep$$

$$\text{nodd: } T_d = [2.5(N-1)+1]ep \text{ for } \Delta \text{ vin}$$

$$T_d = (2.5(N-1)+4)ep \text{ for } \nabla \text{ f vin}$$

**Q6 (a) Explain briefly three different scaling models defined in VLSI design.**

**Answer**

Scaling mode

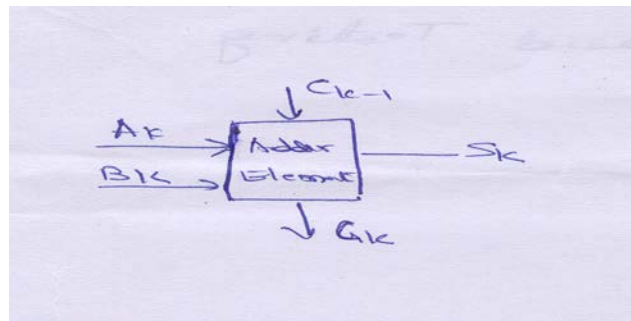
1. Constant electric field scaling model
2. Constant voltage scaling model
3. Combine voltage dimension

**Q6 (b) Draw schematic and stick diagram of an 2-input NOR-gate using CMOS and BiCMOS logic.**

**Answer** Page Number 148 Textbook

**Q7 (a) Design an adder element that can be cascaded to form 'n' bit adder.**

**Answer** Page Number 215 of Text-Book



$$S_k = W_k \bar{C}_{k-1} + H_k C_{k-1}$$

$$C_k = A_k B_k + H_k C_{k-1}$$

$$A/c = Bk$$

$$S_k = C_{k-1}$$

else

$$S_k = \bar{C}_{k-1}$$

$$A/c = B/c$$

$$C_k = Ak = Bk$$

else

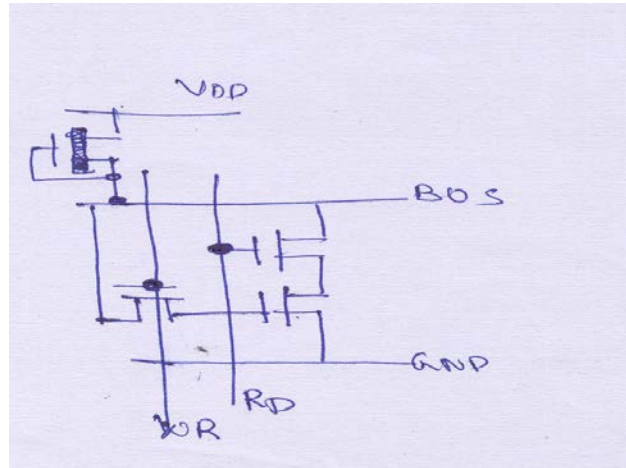
$$C_k = C_{k-1}$$

**Q7 (b) Write the circuit of Manchester carry chain element. Explain briefly with figure the requirement of buffering in cascaded Manchester carry chain circuit.**

**Answer** Page Number 228 of Textbook

**Q8 (a) Write the circuit of three transistor dynamic RAM cell and explain briefly read and write functions.**

**Answer**



**Q8 (b) Write note on factors influencing choice of layer for wiring.**

**Answer** Table 10-6 (Page Number - 311) of Text Book

**Q9 (a) With an example explain sensitized path based testing used for combination logic circuit.**

**Answer**

Sensitized path based Testing

1. Manifestation
2. Propagation
3. Consistency

Page Number 337 of Textbook

**Q9 (b) Explain DRC, Circuit Extractor and Simulator with example.**

**Answer** Page Number 301-303 of Textbook

### Text Book

**Basic VLSI Design, Douglas A. Pucknell and Kamran Eshraghian, PHI, 3rd Edition, 2007**